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C-V/IV and CCE measurements of MCz and FZ p and n type diodes after mixed irradiations

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The set of MCz and Fz p and n type diodes was irradiated first with fast charged hadrons (200 MeV pions or 24 GeV protons) and afterwards with reactor neutrons. The measurements showed that damage of both irradiation particles adds for Neff and leakage current. The space charge of MCz-n detectors after charged hadron irradiations should be positive as the additional irradiation with neutrons reduces the Vfd. The measurements of CCE confirm above observations.

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